Advanced Power MOSFET

FEATURES

■ Avalanche Rugged Technology

■ Rugged Gate Oxide Technology

■ Lower Input Capacitance

■ Improved Gate Charge

■ Extended Safe Operating Area

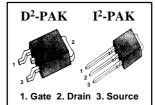
■ Lower Leakage Current : $10 \,\mu\text{A}$ (Max.) @ $V_{DS} = -200 V$

 \blacksquare Low $\mathsf{R}_{\mathsf{DS}(\mathsf{ON})}$: 0.581 Ω (Typ.)

$BV_{DSS} = -200 V$

 $R_{DS(on)} = 0.8 \Omega$

 $I_D = -6.5 A$



Absolute Maximum Ratings

Symbol	Characteristic	Value	Units	
$V_{ t DSS}$	Drain-to-Source Voltage	-200	V	
	Continuous Drain Current (T _C =25°C)	-6.5	^	
I _D	Continuous Drain Current (T _C =100°C)	-4.0	Α	
I _{DM}	Drain Current-Pulsed	-26	Α	
V _{GS}	Gate-to-Source Voltage	<u>+</u> 30	V	
E _{AS}	Single Pulsed Avalanche Energy 2	563	mJ	
I _{AR}	Avalanche Current ①	-6.5	Α	
E _{AR}	Repetitive Avalanche Energy	7.0	mJ	
dv/dt	Peak Diode Recovery dv/dt 3	-5.0	V/ns	
	Total Power Dissipation (T _A =25°C) *	3.1	W	
P_{D}	Total Power Dissipation (T _C =25°C)	70	W	
	Linear Derating Factor	0.56	W/°C	
т т	Operating Junction and	55 to 1450		
T_J , T_STG	Storage Temperature Range	- 55 to +150	0.0	
	Maximum Lead Temp. for Soldering	200	°C	
TL	Purposes, 1/8 " from case for 5-seconds	300		

Thermal Resistance

Symbol	Characteristic	Тур.	Max.	Units
$R_{ hetaJC}$	Junction-to-Case		1.79	
$R_{ heta JA}$	Junction-to-Ambient *		40	°C/W
$R_{ heta JA}$	Junction-to-Ambient		62.5	

^{*} When mounted on the minimum pad size recommended (PCB Mount).



Electrical Characteristics (T_C=25°C unless otherwise specified)

Symbol	Characteristic	Min.	Тур.	Max.	Units	Test Condition
BV _{DSS}	Drain-Source Breakdown Voltage	-200	-		V	$V_{GS} = 0V, I_{D} = -250 \mu A$
$\Delta BV/\Delta T_J$	Breakdown Voltage Temp. Coeff.		-0.17		V/°C	I _D =-250μA See Fig 7
$V_{GS(th)}$	Gate Threshold Voltage	-2.0		-4.0	V	V_{DS} =-5V, I_{D} =-250 μ A
	Gate-Source Leakage, Forward			-100	nA	V _{GS} =-30V
I _{GSS}	Gate-Source Leakage, Reverse			100	ПА	V _{GS} =30V
	Drain to Source Leakage Current			-10	μА	V _{DS} =-200V
I _{DSS}	Drain-to-Source Leakage Current			-100		V_{DS} =-160V, T_{C} =125°C
R _{DS(on)}	Static Drain-Source On-State Resistance			0.8	Ω	V_{GS} =-10V, I_{D} =-3.3A ④
g _{fs}	Forward Transconductance		4.2		Ω	V _{DS} =-40V,I _D =-3.3A ④
C _{iss}	Input Capacitance		740	965		\/ _0\/\/ _ 25\/f_1MU¬
C _{oss}	Output Capacitance		125	185	рF	V_{GS} =0V, V_{DS} =-25V,f =1MH
C _{rss}	Reverse Transfer Capacitance		49	75		See Fig 5
t _{d(on)}	Turn-On Delay Time		14	35		V _{DD} =-100V,I _D =-6.5A,
t _r	Rise Time		22	55	no	
$t_{d(off)}$	Turn-Off Delay Time		41	90	ns	$R_G=12\Omega$
t _f	Fall Time		17	45		See Fig 13 ④ ⑤
Q_g	Total Gate Charge		29	36		V _{DS} =-160V,V _{GS} =-10V,
Q_{gs}	Gate-Source Charge		5.8		nC	I _D =-6.5A
Q_{gd}	Gate-Drain("Miller ") Charge		13.6			See Fig 6 & Fig 12 4 5

Source-Drain Diode Ratings and Characteristics

Symbol	Characteristic	Min.	Тур.	Max.	Units	Test Condition
I _S	Continuous Source Current			-6.5	_	Integral reverse pn-diode
I _{SM}	Pulsed-Source Current ①			-26	А	in the MOSFET
V _{SD}	Diode Forward Voltage 4			-5.0	V	$T_J = 25^{\circ}C, I_S = -6.5A, V_{GS} = 0V$
t _{rr}	Reverse Recovery Time		160		ns	$T_J=25^{\circ}C, I_F=-6.5A$
Q _{rr}	Reverse Recovery Charge		0.96		μС	di _F /dt=100A/μs

- 5 Essentially Independent of Operating Temperature



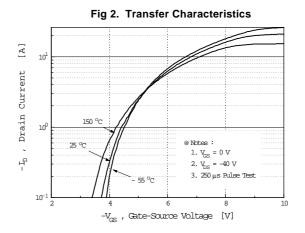
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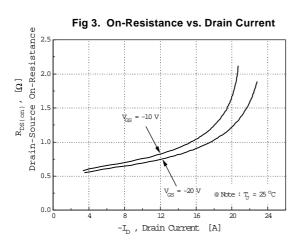
Fig 1. Output Characteristics V_{GS}
-15 V
-10 V
-8.0 V
-7.0 V
-6.0 V
-5.5 V [A] $^{-I_{
m D}}$, Drain Current -5.0 V - 4.5 V @ Notes : 1. 250 μs Pulse Test 2. $T_C = 25$ °C 10-1

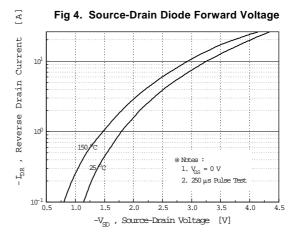
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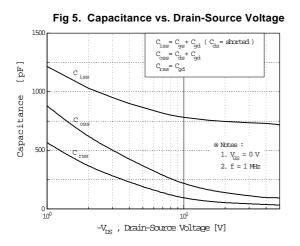
 $-V_{DS}$, Drain-Source Voltage [V]

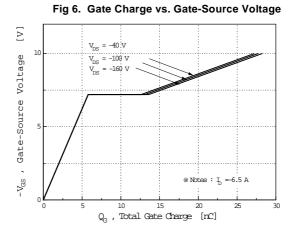
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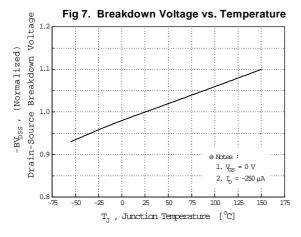


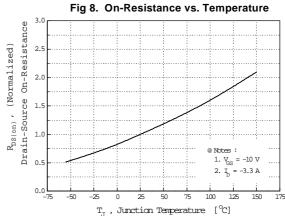


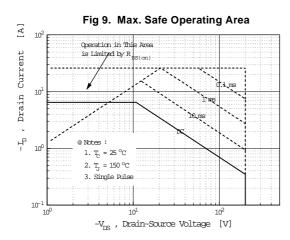


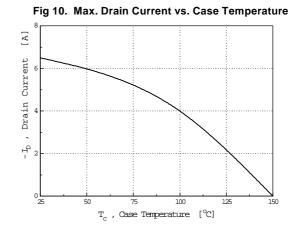












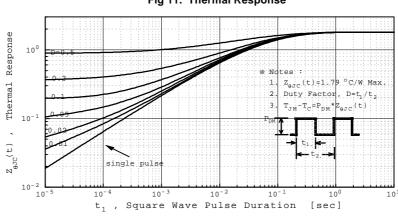


Fig 11. Thermal Response



Fig 12. Gate Charge Test Circuit & Waveform

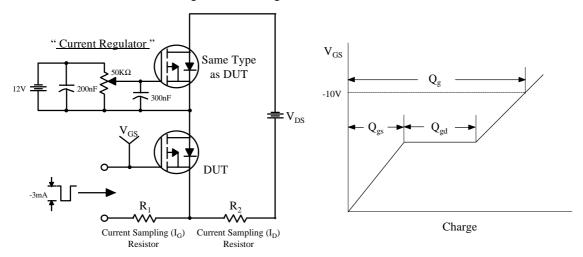


Fig 13. Resistive Switching Test Circuit & Waveforms

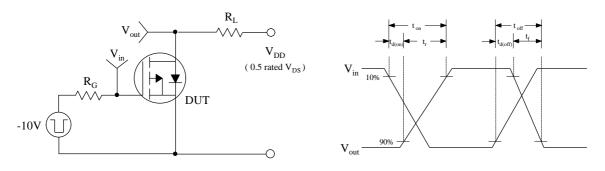


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms

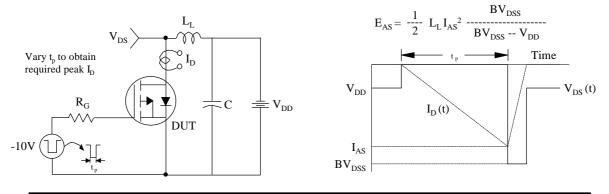
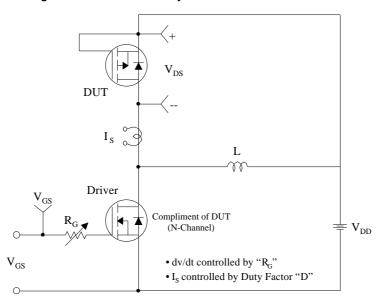
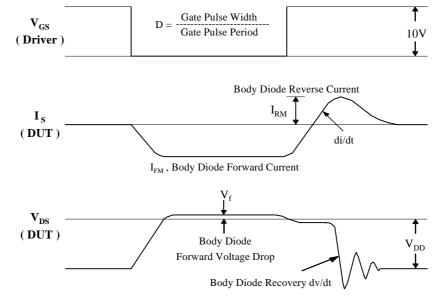




Fig 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms





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